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Ex. Andre' Stevenson

USPT,PGPB,JPAB

((5592007))and (die\$2 or dice\$2) and
signal\$2 and line\$2) and isolation\$2 and
device\$2

USPT,PGPB,JPAB

ll5 and isolation\$2 and device\$2

USPT,PGPB,JPAB

ll5 and isolation\$2 and device\$23.

USPT,PGPB,JPAB

((5592007)) and fuse\$2

USPT,PGPB,JPAB

((5592007)) and (die\$2 or dice\$2) and signal\$2
and line\$2 and power\$2

USPT,PGPB,JPAB

((5592007)) and (die\$2 or dice\$2) and
signal\$2 and line\$2

USPT,PGPB,JPAB

((5592007)) and power\$2

USPT,PGPB,JPAB

((5592007)) and power\$@

USPT,PGPB,JPAB

((5592007))and signal\$2 and transistor\$2 and
diode\$2) and test\$3

USPT,PGPB,JPAB

(5592007) and signal\$2 and transistor\$2 and
diode\$2

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(5592007) and signal\$2 and transistor\$2 and
diode\$2

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(5592007) and locos

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(5592007) and test\$3 and (connect\$2 or
connecting or disconnected\$2 or disconnecting)

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(5592007) and test\$3 and (connect\$2 or
connecting or disconnected)

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((5592007)and signal\$2 and isolation\$2 near
device\$2) and test\$2

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(5592007) and signal\$2 and isolation\$2 near
device\$2

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((5592007)and dice\$2 and wafer and
isolation\$2 near device\$2)and (die\$2 or dice\$2)
near test\$2) and signal\$2 and transistor\$2 and
diode\$2

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((5592007)and dice\$2 and wafer and
isolation\$2 near device\$2) and (die\$2 or dice\$2)
near test\$2

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(dice\$2 and wafer and isolation\$2 near
device\$2) and (die\$2 or dice\$2) near test\$2

USPT,PGPB,JPAB

(5592007) and dice\$2 and wafer and
isolation\$2 near device\$2

USPT,PGPB,JPAB

5592007

USPT,PGPB,JPAB

((dice\$2 and wafer and isolation\$2 near
device\$2)and (die\$2 or dice\$2) near test\$2)and
transistor\$2 and diode\$2) and signal\$2

USPT,PGPB,JPAB

((dice\$2 and wafer and isolation\$2 near
device\$2)and (die\$2 or dice\$2) near test\$2) and
transistor\$2 and diode\$2

USPT,PGPB,JPAB

(dice\$2 and wafer and isolation\$2 near
device\$2) and (die\$2 or dice\$2) near test\$2

USPT,PGPB,JPAB

dice\$2 and wafer and isolation\$2 near device\$2

USPT

(dice\$2 and wafer and isolation\$2 near
device\$2) and (die\$2 or dice\$2) near test\$2

USPT

(dice\$2 and wafer and isolation\$2 near
device\$2) and signal\$2 near line\$2

USPT

dice\$2 and wafer and isolation\$2 near device\$2

USPT

dice\$2 and wafer and isolation\$2 near device\$2
and